

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination	
			10/078,719	YEO ET AL.	
Examiner			Alonzo Chambliss	Art Unit	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,525,942	02-2003	Huang et al.	361/704
*	B	US-5,933,324	08-1999	Barrett, Joseph C.	361/703
*	C	US-5,113,315	05-1992	Capp. Michael L.; et. al.	361/704
*	D	US-5,959,356	09-1999	Oh, Sang Eon	257/738
*	E	US-5,898,217	04-1999	Johnston, Patrick	257/691
*	F	US-6,362,525	03-2002	Rahim, Irfan M.	257/738
*	G	US-5,851,337	12-1998	Chen, Shih-Li	156/275.3
*	H	US-6,198,635	03-2001	Shenoy et al.	361/760
*	I	US-5,741,729	04-1998	Selna, Erich	438/125
*	J	US-6,479,758	11-2002	Arima et al.	174/260
*	K	US-2002/0139571	10-2002	Mizunashi, Harumi	174/255
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 11074407 A	03-1999	Japan	NAKAMURA, TAKASHI	H01L 23/12
*	O	JP 02254747 A	10-1990	Japan	HAMAGUCHI, HIROYUKI	H01L 23/52
*	P	JP 03259543 A	11-1991	Japan	YAMASHITA, MASAHIKO	H01L 21/60
*	Q	JP 2001284488 A	10-2001	Japan	TOKUSHIGE et al.	H01L 23/12
*	R	EP 877419 A2	11-1998	European Patent	RINNE et al.	H01L 21/60
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.